

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY DOCKET NO  
MI22-1171

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Salman Akram et al.

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## U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
Gm	AA	5,750,435	05/12/98	Pan			
	AB	5,716,875	02/10/98	Jones, Jr. et al.			
	AC	5,714,788	02/03/98	Ngaoaram			
	AD	5,705,409	01/06/98	Witek			
	AE	5,672,525	09/30/97	Pan			
	AF	5,599,726	02/04/97	Pan			
	AG	5,571,734	11/05/96	Tseng et al.			
	AH	5,382,533	01/17/95	Ahmad et al.			
	AI	5,225,355	07/06/93	Sugino et al.			
Gm	AJ	3,933,530	01/20/76	Mueller et al.			
	AK						

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

Gm	AR	Improvement of SiO <sub>2</sub> /Si Interface Properties by Fluorine Implantation, K. Ohyu, Y. Nishioka, Y. Ohji, and N. Natsuaki, International Conference on Solid State Devices and Materials, 1988, pp. 607-608. ✓
Sun	AS	The Effect of Fluorine on Gate Dielectric Properties, P.J. Wright, M. Wong and K.C. Saraswat, IEEE 1987, pp. 574-577. ✓
	AT	

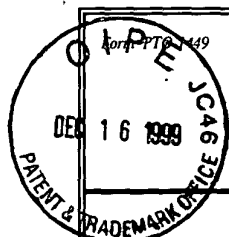
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 U.S. DEPARTMENT OF COMMERCE  
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ATTY. DOCKET NO.  
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LIST OF ART CITED BY APPLICANT  
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 April 14, 1999

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 2812

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*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
SM	AA 5,672,544	9/30/97	Pan	437	200	
	AB 5,369,297	11/29/94	Kusunoki et al.	257	344	
SM	AC 5,814,863	9/29/98	Pan	257	344	
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	AI					
	AJ					
	AK					

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
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	AN						
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